APPENDIX A SPECIFICATIONS

MEASUREMENTS.

Roughness R₂, Arithmetic Average

Max R_a, Maximum of 19 overlapping sections

R₀, Root-Mean-Square (RMS)

R_p, Maximum Height R_v, Maximum Depth

R, Maximum Peak-to-Valley

R₂, Ten-Point Height R₃₂, Six-Point Height

R_h, Height between two points

Waviness Wa, Arithmetic Average

W_p, Root-Mean-Square W_p, Maximum Height W_v, Maximum Depth

W_t, Maximum Peak-to-Valley W_h, Height between two points

Topography

TIR Total Indicator Run-out

Height Height between two points (Step Height)
Average Height Average height of all data points between

Average height of all data points between the measure-

ment cursors relative to the leveled baseline (Delta Aver-

ing)

Slope Rate of change of the profile between two points

Radius Distance from center of curvature of profile arc to the

profile

Area of Peaks Total area bounded by the leveled baseline and the profile

above the baseline

Area of Valleys Total area bounded by the leveled baseline and the profile

below the baseline

Total Area Sum of Area of Peaks and Area of Valleys

Profile Length Length obtained from drawing out the profile into a

straight line

Maximum Height Maximum height of trace between the measurement cur-

sors relative to the zero line

Minimum Height Minimum height of trace between the measurement cur-

sors relative to the zero line

Edge Distance to rising or falling edge or apex from start of

profile

Step Width Width of profile step

Number of Steps

Number of steps between the measurement cursors

Mean Step Height

Mean value of all the steps between the measurement

cursors

Std. Dev. Step Height Standard deviation of all the steps between the measure-

ment cursors

Mean Peak Height

RMS Slope

Average RMS Wavelegth
Standard Deviation Heights

Standard Deviation Heights Bearing Length Ratio Mean value of peak heights

Root-mean-square value of slopes 2π times ratio of RMS deviation of R_q to the RMS slope

Standard deviation of peak heights

Ratio of bearing length to sampling length at chosen value

of Cutting Depth

Cutting Depth Distance below highest peak to reference line giving

chosen value of Bearing Ratio

Peak Count Number of peak/valley pairs per unit length projecting

through a band of chosen width centered about mean line

High Spot Count Number of profile peaks per unit length projecting

through a chosen reference line

Mean Peak Spacing Mean value of the local peak spacing, where peaks are

defined as in Peak Count

Table A-1 Long Wave Cutoff Filter Wavelengths

mm	in.	mm	in.	oun	in.
0.0045	0.0002	0.14	0.006	4.5	0.18
0.008	0.0003	0.25	0.01	8.0	0.3
0.014	0.0006	0.45	0.018	14	0.55
0.025	0.001	0.8	0.03	25	1.0
0.045	0.002	1.4	0.055		
0.08	0.003	2.5	0.1		

Table A-2 Short Wave Cutoff Filter Wavelengths

шш	in.	mm	in.	mm	in.
Default ¹		0.014	0.00056	1.4	0.056
0.00025	0.00001	0.025	0.0010	2.5	0.10
0.00045	0.00002	0.045	0.0018	4.5	0.18
0.00080	0.00003	0.08	0.0030	8.0	0.30
0.0014	0.00006	0.14	0.0056	14	0.56
0.0025	0.00010	0.25	0.010	25	1.0
0.0045	0.00018	0.45	0.018		
0.008	0.00030	0.80	0.030		

¹ Default cutoff filter values differ depending on scan speed and sampling rate. See Table A-3,

Table A-3 Default Short Wave Cutoff Filter Wavelengths

Speed (µm/s)	Sampling Rate (Hz)	Short Wave Cutoff Frequency (Hz)	Short Wave Cutoff Wavelength (µm)
1	50	4	0.25
	100	7.5	0.13
	200	15	0.07
	500	37.5	0.03
	1000	Not Available	Not Available
2	50	4	0.5
	100	7.5	0.27
	200	15	0.13
	500	37.5	0.05
	1000	75	0.03
5	50	4	1.3
	100	7.5	0.67
	200	15	0.33
	500	37.5	0.13
	1000	75	0.07

Table A-3 Default Short Wave Cutoff Filter Wavelengths (continued)

Speed (µm/s)	Sampling Rate (Hz)	Short Wave Cutoff Frequency (Hz)	Short Wave Cutofi Wavelength (µm)
10	50	4	2.5
	100	7.5	1.3
	200	15	0.67
	500	37.5	0.27
	1000	75	0.13
20	50	4	5.0
	100	7.5	2.7
	200	15	1.3
	500	37.5	0.53
	1000	75	0.26
50	50	4	13
	100	7.5	6.7
	200	15	3.3
	500	37. <i>5</i>	1.3
	1000	75	0.67
100	50	4	. 25
	100	7.5	13
	200	15	6.7
	500	37.5	2.7
	1000	75	1.3
200	50	4	50
•	100	7.5	27
	200	15	13
	500	37.5	5.3
	1000	75	2.6
400	50	4	100
	100	7.5	<i>5</i> 3
	200	15	27
	500	37.5	11
	1000	75	53
1000	50	4	250
	100	7.5	130
	200	15	67
	500	37.5	27
	1000	75	13

MICROHEAD MEASUREMENT HEAD

Scan Method	
Stylus Applied Force	

Moving stage, stationary stylus MicroHead sr: 1.0-50 mg MicroHead xr: 0.5-50 mg

Low Force MicroHead II: 0.05-50 mg

Scan Length Scan Speed Sampling Rate Vertical Range	Metric 60 mm 1 μm/sec. to 25 mm/sec. 50, 100, 200, 500, and 1000	
MicroHead sr At 0.008Å Resolution At 0.04Å Resolution At 0.2Å Resolution	±6.5 μm ±32.5 μm 327 μm	±0.26 mil maximum ±1.28 mil maximum 12.8 mil maximum
MicroHead xr At 0.008Å Resolution At 0.08Å Resolution At 0.6Å Resolution	±6.5 μm ±65 μm 1000 μm	±0.26 mil maximum ±2.56 mil maximum 39.4 mil maximum
Low Force MicroHead II At 0.004Å (0.004 μin.) Resolution At 0.016Å (0.008 μin.) Resolution At 0.08Å (0.04 μin.) Resolution	±3.2 μm ±13 μm 131 μm	±0.13 mil maximum ±0.51 mil maximum 5.2 mil maximum
Vertical Linearity, below 2000Å Vertical Linearity, above 2000Å	10Å ±0.5%	0.04 μin ±0.5%

NOTE:

Because the instrument linearity guarantee is significantly smaller than the uncertainty of the step height standards available in the range of typical use of the instrument, step height standards cannot be used to verify the linearity of the instrument.

Horizontal Resolution	Metric	English
At 1 µm/sec. scan speed	0.01 μm (100Å)	0.4 µin

^{1.} The vertical resolutions listed here represent the smallest discrete measurable units for each vertical range. Actual measurements will reflect somewhat higher resolutions due to the effects of noise and surface scan characteristics.

Stylus Control

Programmable Force

Range

1.0-50 mg (MicroHead sr)

0.5-50 mg (MicroHead xr)

0.05-50 mg (Low Force MicroHead II)

Resolution

 $0.01~\mathrm{mg}$

Full retract between scans Programmable descent rate

Variable Sample Image Magnification

MicroHead sr: top or side-view optics

90°: 115-465x and 185-750x

45°: 95-410x

MicroHead xr: dual-view optics 90°: 115-465x and 185-750x

45°: 95-410x

MicroHead xr: dual-view optics 90°: 115-465x and 185-750x

45°: 95-410x

SAMPLE HANDLING

X-Y

Manual Control

Unlimited programmable locations

Via trackball or keyboard

Maximum Sample Size

(Standard Conguration)

Maximum Sample Size (Open Frame Configuration)

Maximum Sample Weight

Throat Depth

Throat Height, incl. Rotary Stage

X,Y Maximum Travel X,Y Positioning Speed Motorized Stage Rotation

Angle Resolution

Leveling

Vacuum Hold-Down of Sample Custom Fixturing Interface

Metric

254 x 254 mm $10 \times 10 \text{ in.}$

Note: 355 x 355 mm (14 x 14 in.) with side panel removed Stylus can access any part of a 150-mm (8.2-in.) round

English

sample without sample repositioning. 430 x 430 mm 17×17 in.

Note: 480 x 480 mm(19 x 19 in) with side panel re-

moved.

2.2 kg. 5 lb. 228 mm 9 in.

63.5 mm 2.5 in. 150 mm бin. Variable up to 25 mm/sec. 1 in /sec

0.001°

Electronic leveling of traces is standard. Automatic mechanical leveling of sample with Motorized Level and

Rotation Option

Standard

Three 8-32 UNC 2B threaded holes on 3.16-in. diameter

circle, 90° apart.

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MEASUREMENT CONTROL

Manual/Single Scan Mode Repeat and Average Mode

Continuous or segmented scan, from recipe Scan repeated up to ten times and averaged

DATA STORAGE

Hard Disk Diskette

Storage Requirements

850 MB. Stores over 20,000 scans at 1000 points each. 1.44 MB, 3.5 in. Data storage limited to approximately 100 recipes and 200 scans at 1000 points each. (300 scans

per diskette dedicated to data.)
The following figures are estimates only.

DOS Operating System: approx. 6 KB
Microsoft Windows program: approx. 10 MB
Tencor P-11 Profiler program: approx. 11 KB

Recipe: 215 bytes

Single-scan data: 652 bytes plus trace data

Trace data: Trace data storage requirements are added to

that for the scan data.

2D trace data: minimum 2K bytes for the first 505 data points plus 4 times the number of data points thereafter 3D trace data: 2122 bytes minimum plus 2048-byte in-

crements

32 bytes per trace (range 1 to 210 inclusive)

4 bytes per data point

Approximate number of data points = number of traces \times

scan length × sampling rate/scan speed

DATA ANALYSIS

Interactive Graph

Delta Averaging or Leveling Zoom Box Data Expansion Data Catalog Metric/English Units Two cursor read-out. Cursors move independently or in tandem.

Each cursor is expandable into a region for measurement.

Portion of a graph can be magnified.

Immediate data retrieval and display from catalog.

Parameters displayed in preprogrammed metric or English units; independent selection of horizontal and ver-

tical parameters.

EQUIPMENT SPECIFICATIONS

Processor Pentium 100-MHz microprocessor (subject to change).

Runs MS-DOS version 6.22

RAM 16 MB Monitor 15 in. SVGA

Displays magnified image of the sample or output data. Initial data trace or cross-hair identification of stylus location relative to stage can be superimposed on sample

image.

High resolution

Color data display, user-selectable colors .

Standard Keyboard
Vibration Isolation Table

Enhanced 101 AT with trackball

A custom instrument table

Real-Time Clock Battery-backed clock provides date and time of day

PHYSICAL SPECIFICATIONS

	Metric	English
Dimensions, standard configuration		
Width	57 cm	23 in.
Height	46 cm	17.5 in.
Depth	84 cm	34 in.
Dimensions, Open Frame configuration	, with isolation hood in place	
Width	74 cm	29 in.
Height	46 cm	17.5 in.
Depth	90 cm	35 in.
Weight		
Instrument	68 kg	150 lb.
Shipping Weight	127 kg	280 lb.
Electrical	90-110 V, 50/60 Hz	
	110-130 V, 50/60 Hz	
	180-260 V, 50/60 Hz	
Power requirements	150 VA	